

- 2 L5: (377) 4 and (dummy sacrificial)
- 2 L6: (207) 5 and interconnect
- 2 L7: (1) 09/244788
- 2 L8: (1) 10/436921
- 2 L9: (18) 6 and dist. 3

3 Failed

	<input checked="" type="checkbox"/> Патент	<input type="checkbox"/> Свидетельство	<input type="checkbox"/> Декларация	
<input checked="" type="checkbox"/> GBs	<input type="checkbox"/> USPAT	<input type="checkbox"/> US PG PUB	<input type="checkbox"/> EPO	<input type="checkbox"/> IPO
<input checked="" type="checkbox"/> Патент <input type="checkbox"/> Свидетельство <input type="checkbox"/> Декларация				
<input checked="" type="checkbox"/> Highlight of the most interesting				

U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XR	Retrieval C	Inventor	S	C	P	3	4	5
1	1	US 200301127	20031127	10	Sacrificial inlay process for improved integration of	438/622	438/619;		Adem, Ercan et al.	✓	✓	✓	✓	✓	✓
	2	US 20030219968					438/638								
2	2	US 20020106886	20020808	11	Planarized semiconductor interconnect topography and	438/618	257/E21.304;		Sethuraman, Anantha R. et al.	✓	✓	✓	✓	✓	✓
3	3	US 6717267	20040406	49	Semiconductor device having multilayer interconnection B1	257/758	257/760;		Kunikiyo, Tatsuya	✓	✓	✓	✓	✓	✓
4	4	US 6710443	20040323	15	INTEGRATED CIRCUIT PROVIDING THERMALLY	257/712	257/181;		Rost, Timothy A. et al.	✓	✓	✓	✓	✓	✓
5	5	US 6693357	20040217	20	Methods and semiconductor devices with wiring layer fill B1	257/773	257/762;		Borst, Christopher Lyle et al.	✓	✓	✓	✓	✓	✓
6	6	US 6664642	20031216	43	Semiconductor integrated circuit device B2	257/776	257/758;		Koubuchi, Yasushi et al.	✓	✓	✓	✓	✓	✓
7	7	US 6660629	20031209	7	Chemical mechanical polishing method for B2	438/634	257/E21.304;		Lin, Bih-Tiao	✓	✓	✓	✓	✓	✓
8	8	US 6600229	20030729	13	Planarizers for spin etch planarization of electronic B2	257/762	257/752;		Mukherjee, Shyama et al.	✓	✓	✓	✓	✓	✓
9	9	US 6537923	20030325	14	Process for forming integrated circuit structure B1	438/758	438/479;		Bhatt, Hemanshu D. et al.	✓	✓	✓	✓	✓	✓
10	10	US 6503827	20030107	12	Method of reducing planarization defects B1	438/631	257/E21.583;		Bombardier, Susan G. et al.	✓	✓	✓	✓	✓	✓
11	11	US 6472306	20021029	12	Method of forming a dual damascene opening using B1	438/623	438/622;		Lee, Shyh-Dar et al.	✓	✓	✓	✓	✓	✓
12	12	US 6436807	20020820	8	Method for making an interconnect layer and a B1	438/619	257/E21.58;		Cwynar, Donald Thomas et al.	✓	✓	✓	✓	✓	✓
13	13	US 6420258	20020716	8	Selective growth of copper for advanced metallization B1	438/622	438/625;		Chen, Sheng Hsiung et al.	✓	✓	✓	✓	✓	✓
14	14	US 6417095	20020709	7	Method for fabricating a dual damascene structure B1	438/633	438/616;		Chen, Chung-Tai	✓	✓	✓	✓	✓	✓
15	15	US 6413847	20020702	11	Method of forming dummy	438/598	438/618;		Yeh, Tsuei-Chi et al.	✓	✓	✓	✓	✓	✓